





#### 30V N-CHANNEL ENHANCEMENT MODE MOSFET

## **Product Summary**

V <sub>(BR)DSS</sub>	R <sub>DS(on) max</sub>	I <sub>D</sub> T <sub>A</sub> = +25°C	
30V	29mΩ @ V <sub>GS</sub> = 10V	5.6A	
307	$35m\Omega$ @ $V_{GS} = 4.5V$	4.8A	

### **Description**

This new generation MOSFET has been designed to minimize the on-state resistance ( $R_{DS(ON)}$ ) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

# **Applications**

- DC Motor Control
- DC-AC Inverters

# **Features and Benefits**

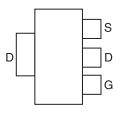
- Low On-Resistance
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

### **Mechanical Data**

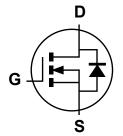
- Case: SOT223
- Case Material: Molded Plastic, "Green" Molding Compound.
   UL Flammability Classification Rating 94V-0 (Note 1)
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See diagram below
- Terminals: Finish Matte Tin annealed over Copper lead frame.
   Solderable per MIL-STD-202, Method 208 @3
- Weight: 0.112 grams (approximate)







Pin Out - Top View



**Equivalent Circuit** 

# Ordering Information (Note 4)

Part Number	Qualification	Case	Packaging
DMN3032LE-13	Standard	SOT223	2,500 / Tape & Reel

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- See http://www.diodes.com/quality/lead\_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

# Marking Information





O!! = Manufacturer's Marking
N3032L = Marking Code
YWW = Date Code Marking for SAT (Shanghai Assembly/ Test site)
YWW = Date Code Marking for CAT (Chengdu Assembly/ Test site)
Y or Y = Year (ex: 3 = 2013)
WW = Week (01 - 53)



# 

Characteristic	Symbol	Value	Units	
Drain-Source Voltage		V <sub>DSS</sub>	30	V
Gate-Source Voltage	V <sub>GSS</sub>	±20	V	
Continuous Drain Current (Note 5) // = 10//	T <sub>A</sub> = +25°C T <sub>A</sub> = +70°C	I <sub>D</sub>	5.6 4.1	А
Continuous Drain Current (Note 5) V <sub>GS</sub> = 10V	T <sub>C</sub> = +25°C T <sub>C</sub> = +70°C	I <sub>D</sub>	15.4 12.1	А
Maximum Continuous Body Diode Forward Current (Note 5)	I <sub>S</sub>	1.5	Α	
Pulsed Drain Current (10µs pulse, duty cycle = 1%)	I <sub>DM</sub>	25	A	

# Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 5)	Ta = +25°C	P <sub>D</sub>	1.8	W
Total Fower Dissipation (Note 3)	Ta = +70°C		1.1	
Thermal Resistance, Junction to Ambient (Note 5)		$R_{ heta JA}$	69	°C/W
Total Power Dissipation (Note 5)		P <sub>D</sub>	14	W
Thermal Resistance, Junction to Case (Note 5)		$R_{ heta JC}$	8.7	°C/W
Operating and Storage Temperature Range		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C

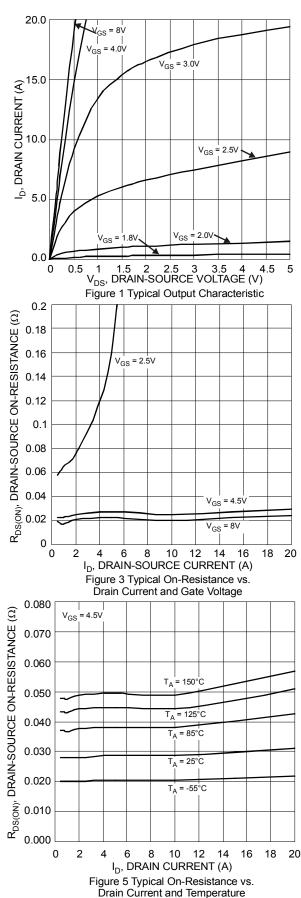
# **Electrical Characteristics** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

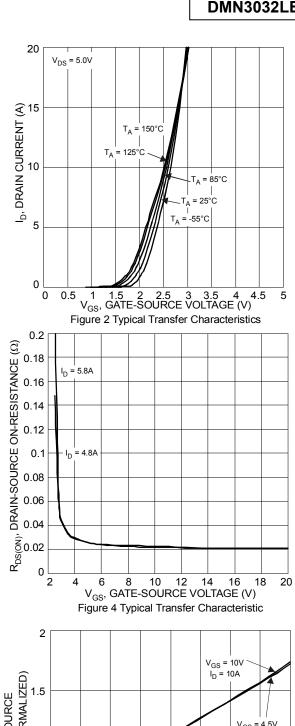
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 6)						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	_	_	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	_	1	μA	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS}$ = ±20V, $V_{DS}$ = 0V
ON CHARACTERISTICS (Note 6)						
Gate Threshold Voltage	$V_{GS(th)}$	1	_	2	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
Static Drain-Source On-Resistance	D	_	22	29	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 3.2A
Static Dialii-Source Oil-Resistance	R <sub>DS (ON)</sub>	_	27	35	11122	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 2.8A
Forward Transfer Admittance	Y <sub>fs</sub>	_	7	_	S	V <sub>DS</sub> = 5V, I <sub>D</sub> = 5.8A
Diode Forward Voltage	$V_{SD}$	_	0.7	1.5	V	V <sub>GS</sub> = 0V, I <sub>S</sub> = 1A
DYNAMIC CHARACTERISTICS (Note 7)						
Input Capacitance	C <sub>iss</sub>	_	498	_		V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V f = 1MHz
Output Capacitance	Coss	_	52	_	pF	
Reverse Transfer Capacitance	C <sub>rss</sub>	_	45	_		
Gate Resistnace	$R_g$	_	2.2	_	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$
Total Gate Charge	$Q_g$	_	11.3	_		$V_{DS} = 15V$ , $V_{GS} = 10V$ , $I_{D} = 5.8A$
Gate-Source Charge	$Q_{gs}$	_	1.4	_	nC	
Gate-Drain Charge	$Q_{gd}$	_	2.1	_		
Turn-On Delay Time	t <sub>D(on)</sub>	_	2.3	_		V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V,
Turn-On Rise Time	t <sub>r</sub>	_	3.9	_	no	
Turn-Off Delay Time	t <sub>D(off)</sub>	_	10	_	ns	$R_L = 2.6\Omega, R_G = 3\Omega$
Turn-Off Fall Time	t <sub>f</sub>		1.9			

5. Device mounted on FR-4 substrate PC board, 2oz copper, with thermal vias to bottom layer 1inch square copper plate 6 .Short duration pulse test used to minimize self-heating effect. Notes:

<sup>7.</sup> Guaranteed by design. Not subject to production testing.







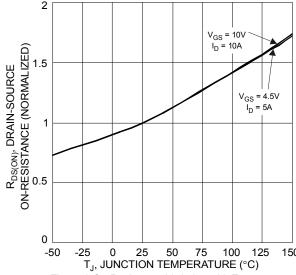
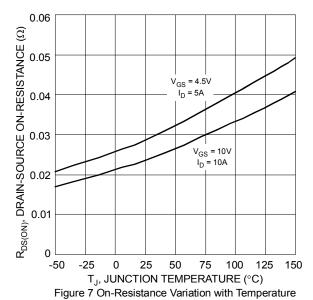
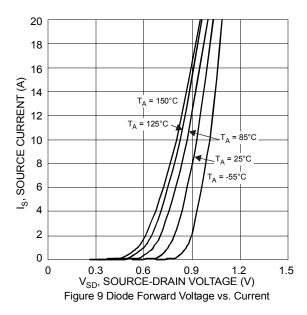
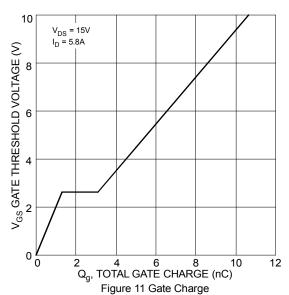


Figure 6 On-Resistance Variation with Temperature









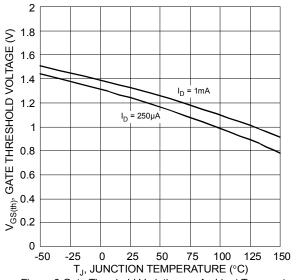
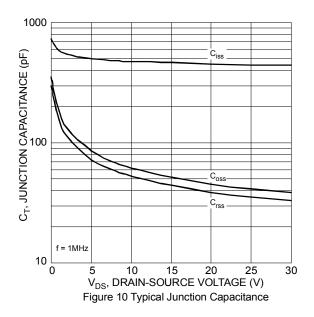
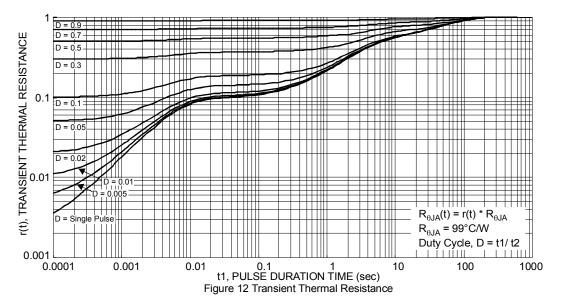


Figure 8 Gate Threshold Variation vs. Ambient Temperature

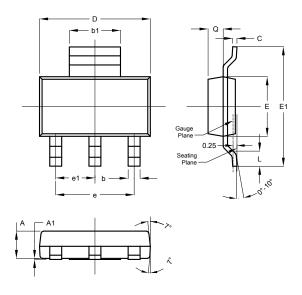






# **Package Outline Dimensions**

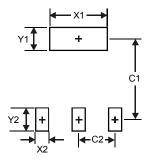
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



SOT223						
Dim	Min	Max	Тур			
Α	1.55	1.65	1.60			
A1	0.010	0.15	0.05			
b	0.60	0.80	0.70			
b1	2.90	3.10	3.00			
С	0.20	0.30	0.25			
D	6.45	6.55	6.50			
Е	3.45	3.55	3.50			
E1	6.90	7.10	7.00			
е	-	-	4.60			
e1	-	-	2.30			
L	0.85	1.05	0.95			
Q	0.84	0.94	0.89			
All Dimensions in mm						

# **Suggested Pad Layout**

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
X1	3.3
X2	1.2
Y1	1.6
Y2	1.6
C1	6.4
C2	2.3



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